

1046 U.S. PTO
10/003180
10/30/01

BEST AVAILABLE COPY

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10003180	10/30/2001	324	710	2133 2950	<i>Decady</i>

APPLICANTS: Park Heon-Deok; An Sang-Bae; Jeon Jae-Kuk;

RDP

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

REPUBLIC OF KOREA 01-3749 01/26/2001

PG-PUB	DO NOT PUBLISH	RESCIND	
Foreign priority claimed		<input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no	9898-197
Verified and Acknowledged Examiner's initials			
TITLE : Semiconductor test system and method for effectively testing a semiconductor device having many pins			
U.S. DEPT. OF COMM./PAT. & TM-PTO-436 (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
		Sheets Drwg.	Figs.Drwg.
Primary Examiner		Print Fig.	
PREPARED FOR ISSUE		Application Examiner	
WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.			
DISCLAIMER		<input type="checkbox"/> TERMINAL	

FILED WITH: DISK (CRF) CD-ROM
(Attached in pocket on right inside flap)